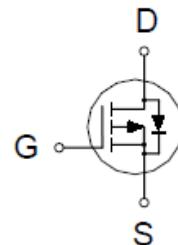
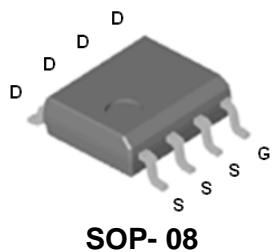


P2003EV8

P-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-30V	20mΩ @ $V_{GS} = -10V$	-10A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 25	
Continuous Drain Current $T_A = 25^\circ C$	I_D	-10	A
$T_A = 70^\circ C$	I_D	-8	
Pulsed Drain Current ¹	I_{DM}	-55	
Avalanche Current	I_{AS}	-29	
Avalanche Energy	E_{AS}	43	mJ
Power Dissipation $T_A = 25^\circ C$	P_D	3	W
$T_A = 70^\circ C$	P_D	2	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		25	°C / W
Junction-to-Ambient	$R_{\theta JA}$		40	

¹Pulse width limited by maximum junction temperature.

P2003EV8

P-Channel Enhancement Mode MOSFET

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1.0	-1.5	-3.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 25\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			-10	
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -7\text{A}$		25	35	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -10\text{A}$		15	20	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -10\text{V}, I_D = -10\text{A}$		24		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1\text{MHz}$		1490		pF
Output Capacitance	C_{oss}			301		
Reverse Transfer Capacitance	C_{rss}			190		
Gate Resistance	R_g	$V_{\text{GS}} = 15\text{mV}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		7.8	9	Ω
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, I_D = -10\text{A}, V_{\text{GS}} = -10\text{V}$		26		nC
Gate-Source Charge ²	Q_{gs}			4		
Gate-Drain Charge ²	Q_{gd}			5		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -15\text{V}, I_D \approx -1\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GS}} = 6\Omega$		5.7		nS
Rise Time ²	t_r			10		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			18		
Fall Time ²	t_f			5		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-2.5	A
Forward Voltage ¹	V_{SD}	$I_F = -1\text{A}, V_{\text{GS}} = 0\text{V}$			-1.2	V

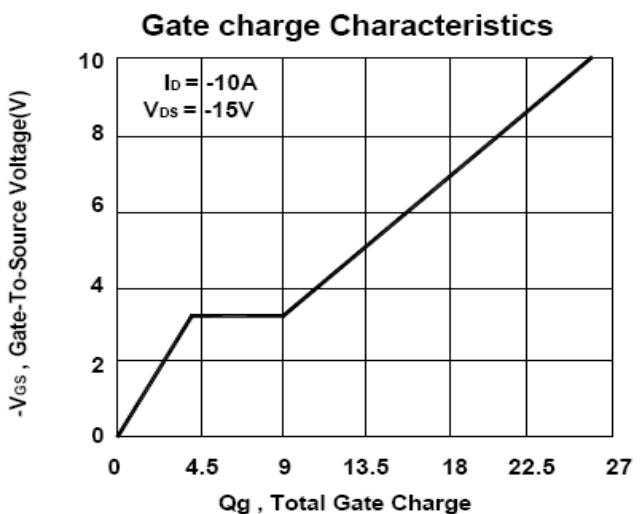
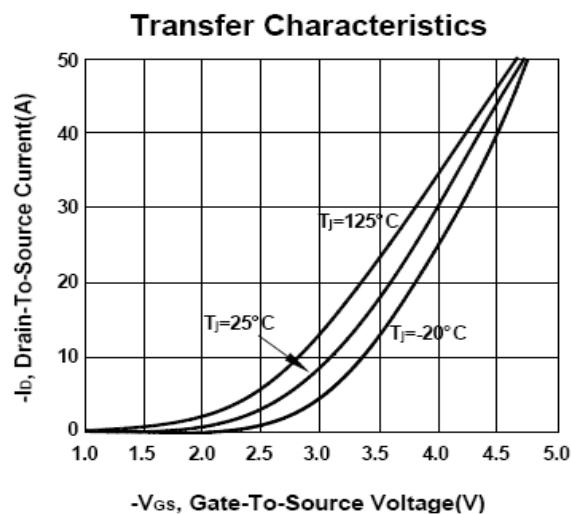
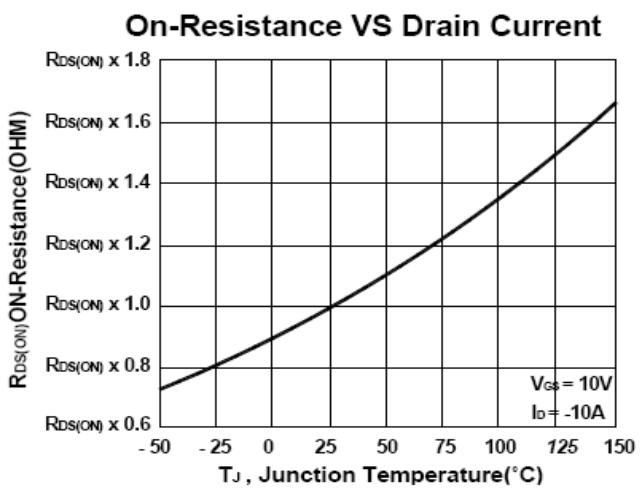
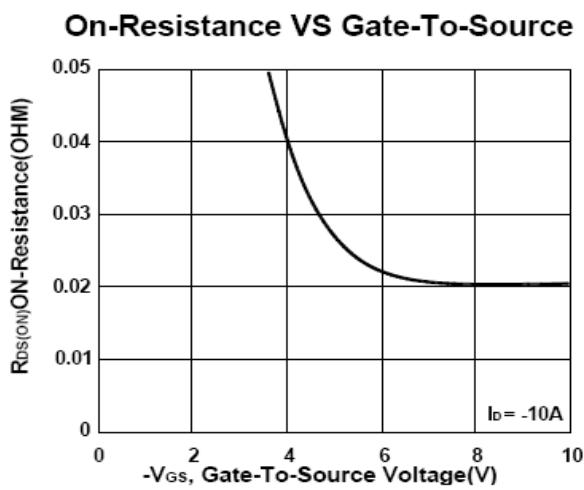
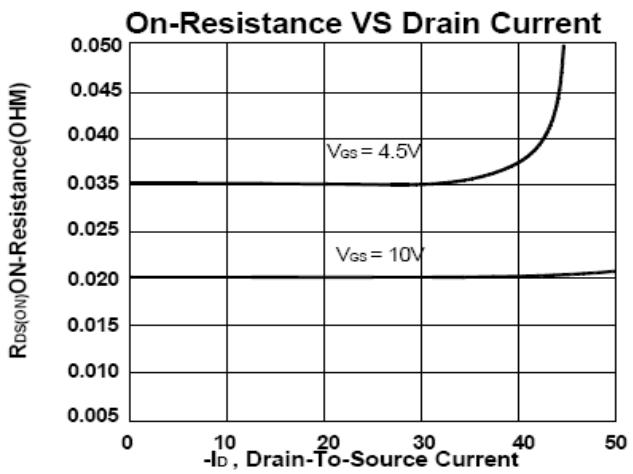
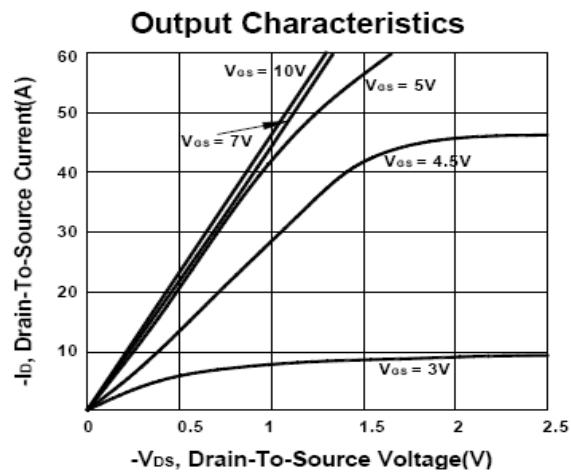
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

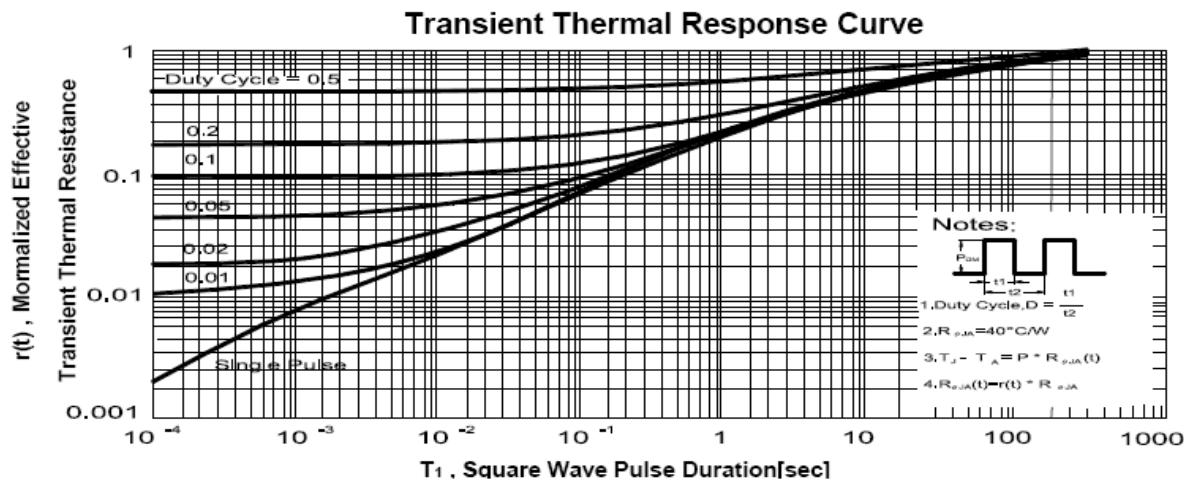
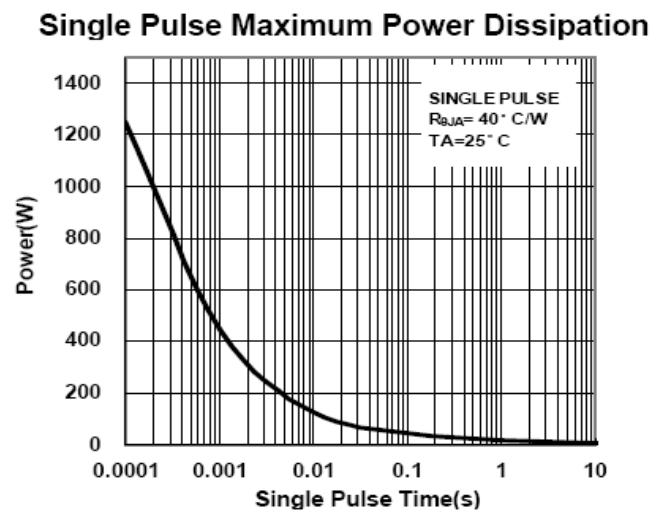
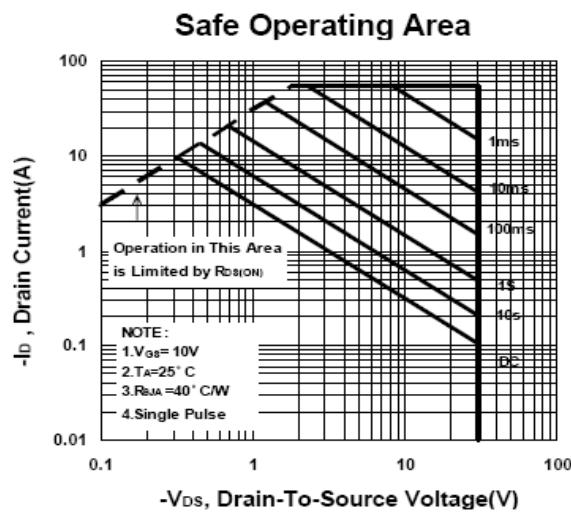
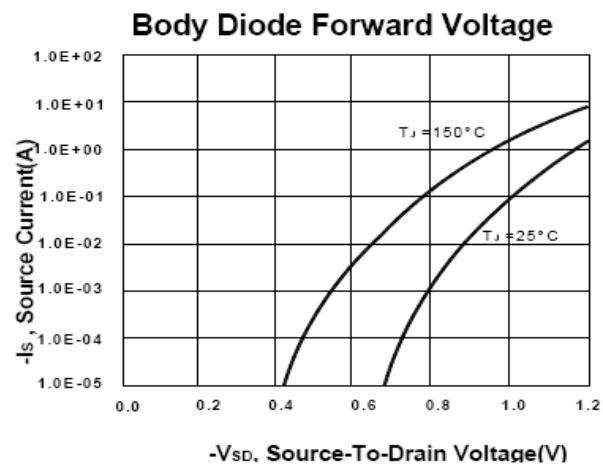
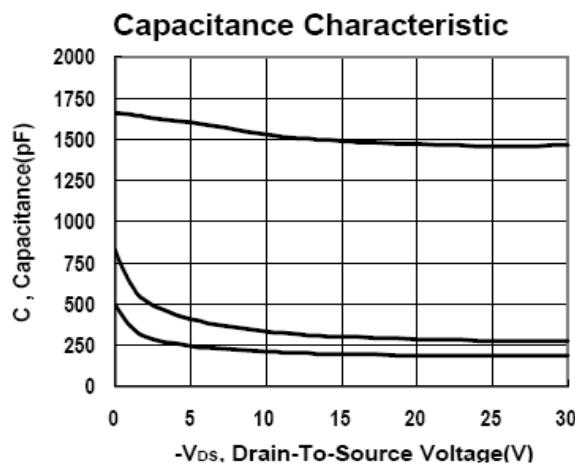
P2003EV8

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Package Dimension

SOP-8 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.8	4.9	5.0	H	0.4	0.6	0.93
B	3.8	3.9	4.0	I	0.19	0.21	0.25
C	5.79	6.0	6.2	J	0.25	0.375	0.5
D	0.33	0.4	0.51	K	0°	3°	18°
E	1.25	1.27	1.29				
F	1.1	1.3	1.65				
G	0.05	0.15	0.25				

